

Features

- CRM(CQ) Super_Junction technology
- Much lower $R_{on} \cdot A$ performance for On-state efficiency
- Better efficiency due to very low FOM
- Qualified for industrial grade applications according to JEDEC

Applications

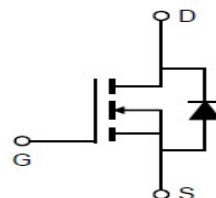
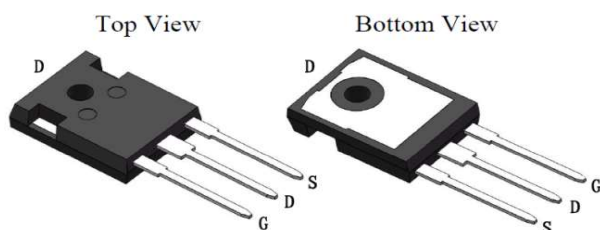
- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Charger
- Power Supply

Product Summary

$V_{DS,min}$	600V
$R_{DS(on),typ}$	25mΩ
I_D	83A

100% DVDS Tested

100% Avalanche Tested



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRJQ30N60G2	CRJQ30N60G2	TO-247-3L	Tube	N/A	N/A	25pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	600	V
Continuous drain current ¹⁾ $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	I_D	83 57	A
Pulsed drain current ²⁾ ($T_C = 25^\circ\text{C}$, t_p limited by $T_{j,max}$)	$I_{D,pulse}$	332	A
Avalanche energy, single pulse ($L=30\text{mH}$)	E_{AS}	1200	mJ
MOSFET dv/dt ruggedness	dv/dt	50	V/ns
Gate-Source voltage	V_{GS}	± 30	V
Power dissipation ($T_C = 25^\circ\text{C}$)	P_{tot}	595	W
Continuous diode forward current ($T_C = 25^\circ\text{C}$)	I_S	83	A
Diode pulse current ²⁾ ($T_C = 25^\circ\text{C}$)	$I_{S,pulse}$	332	A
Recovery diode dv/dt ³⁾	dv/dt	50	V/ns
Operating junction and storage temperature	T_j, T_{stg}	-55...+150	$^\circ\text{C}$

1) Limited by $T_{j,max}$. Maximum Duty Cycle $D = 0.50$

2) Pulse width t_p limited by $T_{j,max}$

3) Identical low side and high side switch with identical R_g

Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case	R_{thJC}	-	0.15	0.21	°C/W	
Thermal resistance, junction – ambient	R_{thJA}	-	-	46	°C/W	

Electrical Characteristic (at $T_j = 25\text{ }^{\circ}\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV_{DSS}	600	-	-	V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	3	-	4	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	$V_{DS}=600V, V_{GS}=0V$ $T_j=25^{\circ}\text{C}$
		-	15	-		$T_j=150^{\circ}\text{C}$
Gate-source leakage current	I_{GSS}	-	-	± 100	nA	$V_{GS}=\pm 30V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	25	30	mΩ	$V_{GS}=10V, I_D=42A,$ $T_j=25^{\circ}\text{C}$
		-	63	-		$T_j=150^{\circ}\text{C}$
Transconductance	g_{fs}	-	77	-	S	$V_{DS}=20V, I_D=42A$

Dynamic Characteristic

Input Capacitance	C_{iss}	-	6445	-	pF	$V_{GS}=0V, V_{DS}=100V,$ $f=1\text{MHz}$
Output Capacitance	C_{oss}	-	320	-		
Reverse Transfer Capacitance	C_{rss}	-	11	-		
Gate Total Charge	Q_g	-	203	-	nC	$V_{GS}=10V, V_{DS}=480V,$ $I_D=42A$
Gate-Source charge	Q_{gs}	-	40	-		
Gate-Drain charge	Q_{gd}	-	87	-		
Gate plateau voltage	$V_{plateau}$	-	5.5	-	V	
Turn-on delay time	$t_{d(on)}$	-	110	-	ns	$V_{GS}=10V, I_D=42A,$ $V_{DS}=400V, R_g=27\Omega$
Rise time	t_r	-	97	-		
Turn-off delay time	$t_{d(off)}$	-	716	-		
Fall time	t_f	-	132	-		
Gate resistance	$R_{g,int}$	-	0.96	-	Ω	$f=1\text{MHz}$

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	0.6	0.87	1.1	V	$V_{GS}=0V, I_{SD}=42A$
Body Diode Reverse Recovery Time	t_{rr}	-	535		ns	$I_{SD}=42A$ $di_F/dt=100A/\mu s$ $V_{DS}=400V$
Body Diode Reverse Recovery Charge	Q_{rr}	-	11		μC	

Typical Performance Characteristics

Fig 1: Output Characteristics ($T_j=25^\circ\text{C}$)

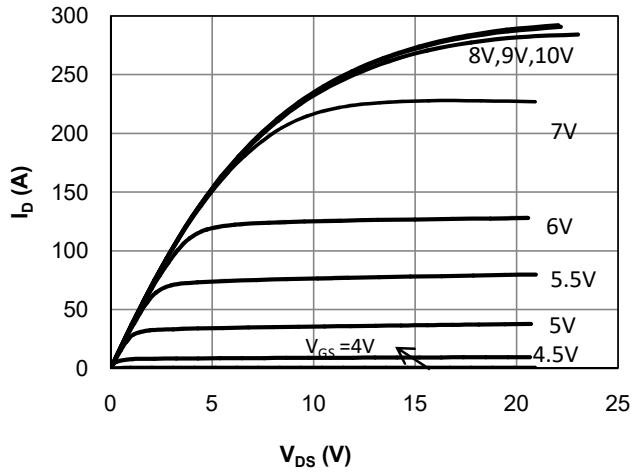


Fig 2: Output Characteristics ($T_j=150^\circ\text{C}$)

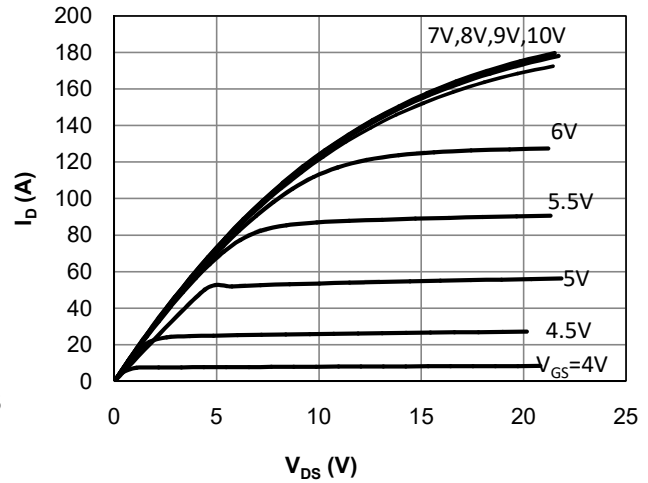


Fig 3: Transfer Characteristics

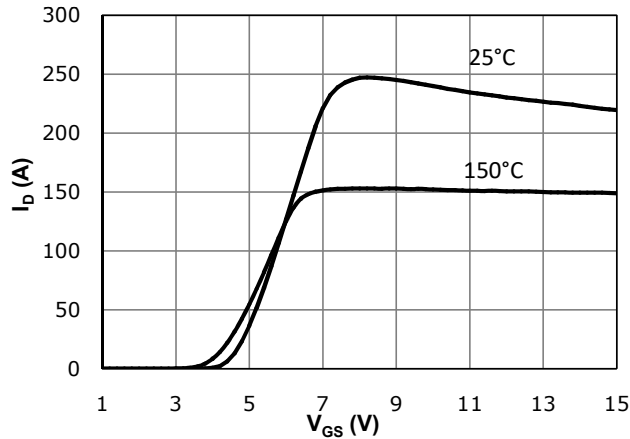


Fig 4: V_{TH} vs. T_j Temperature Characteristics

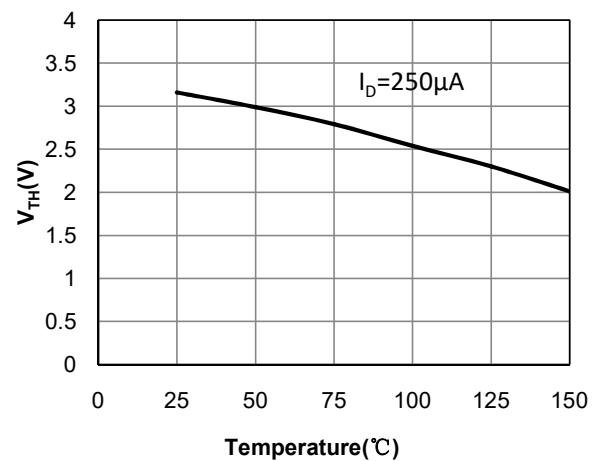


Fig 5: $R_{DS(on)}$ vs. I_{DS} Characteristics ($T_j=25^\circ\text{C}$)

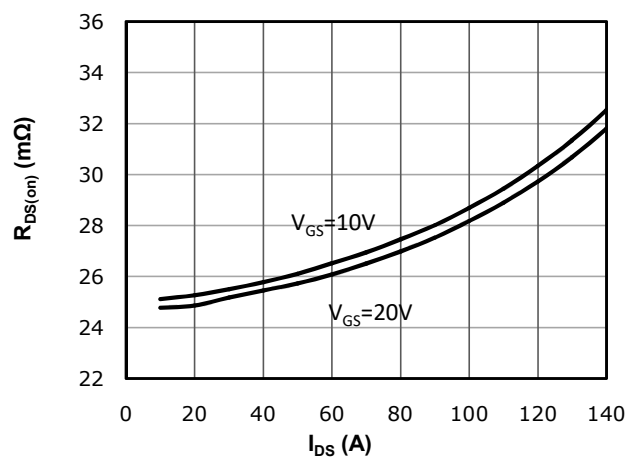


Fig 6: $R_{DS(on)}$ vs. Temperature

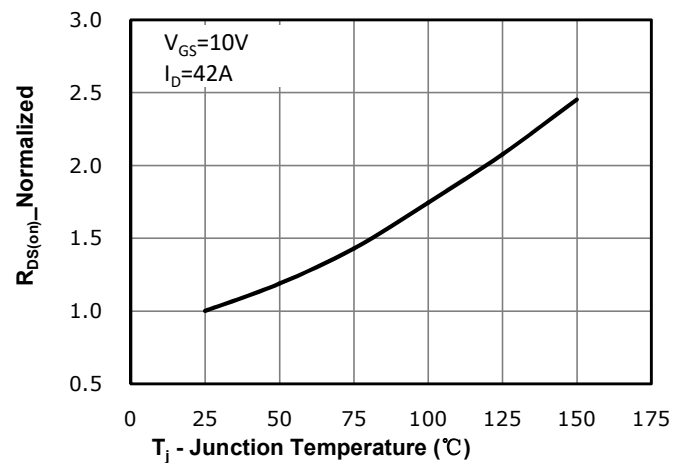


Fig 7: BV_{DSS} vs. Temperature

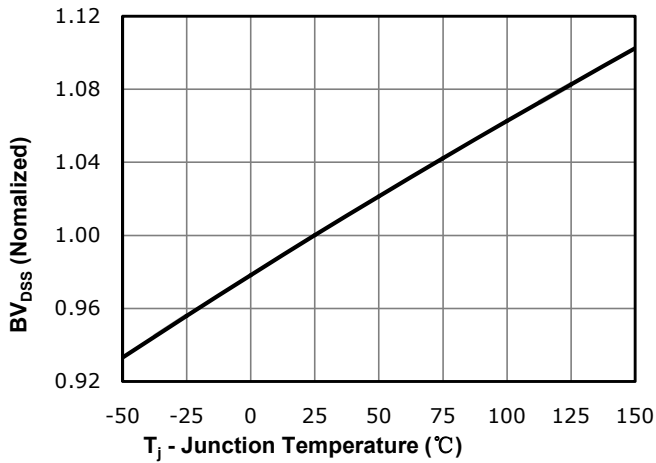


Fig 8: $R_{DS(on)}$ vs. Gate Voltage

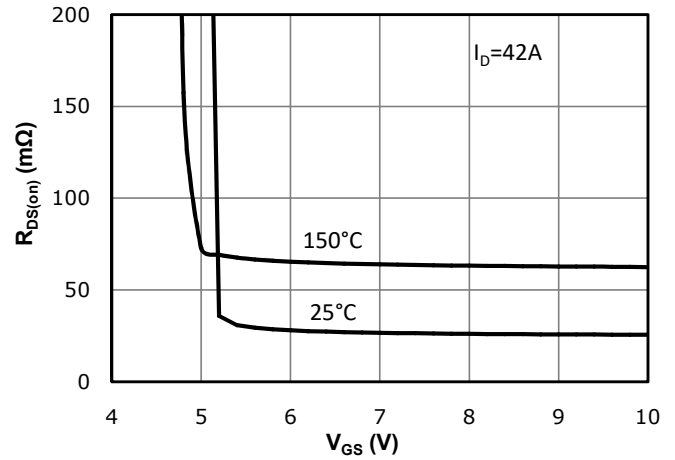


Fig 9: Body-diode Forward Characteristics

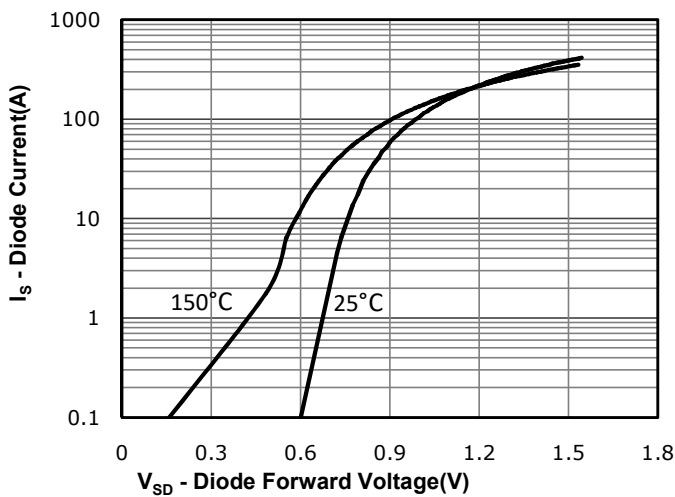


Fig 10: Gate Charge Characteristics

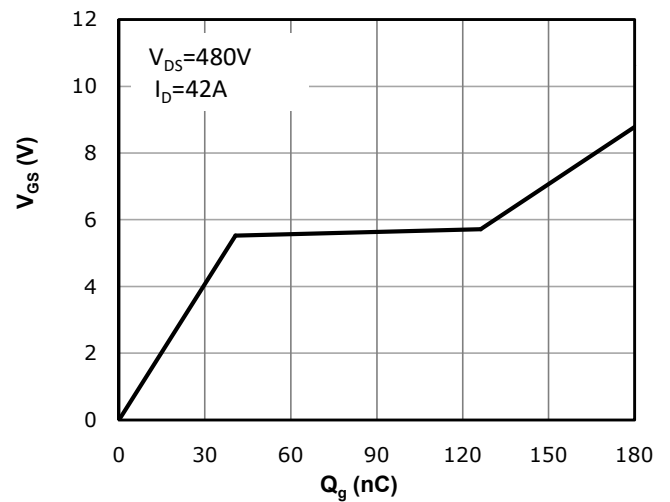


Fig 11: Capacitance Characteristics

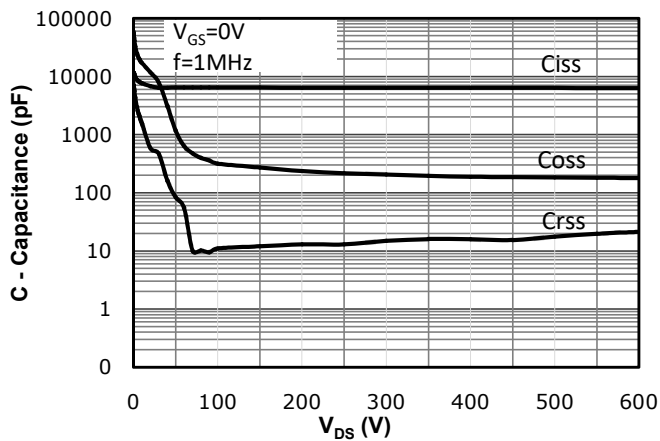


Fig 12: Safe Operating Area

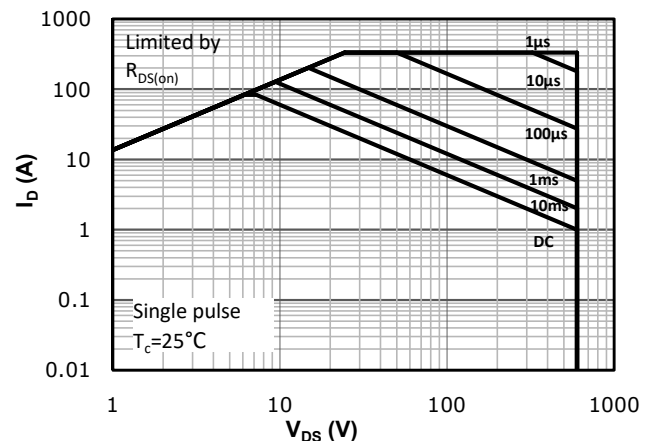
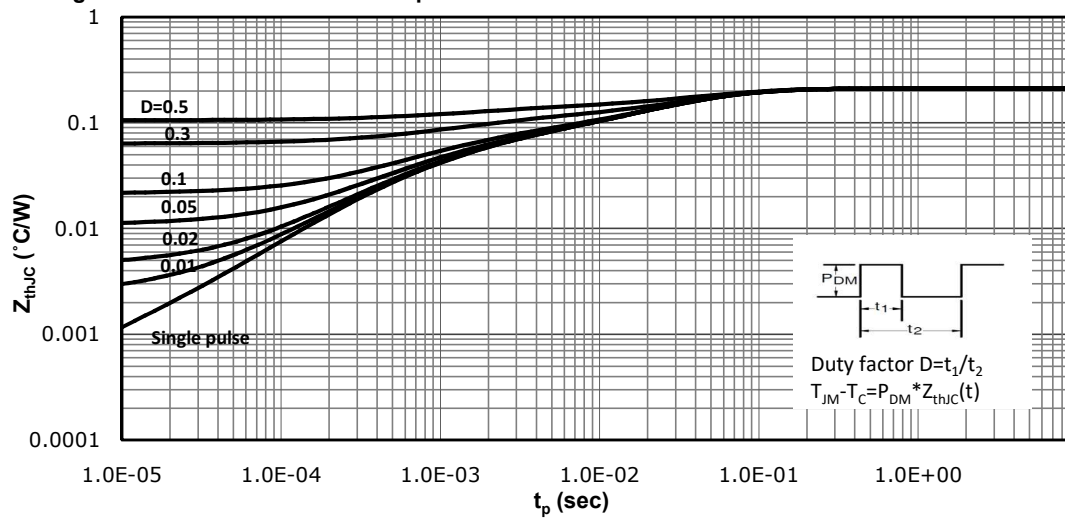
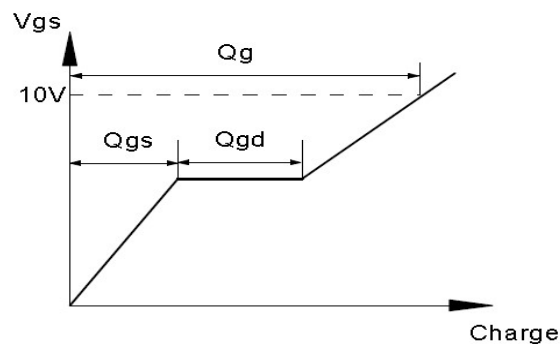
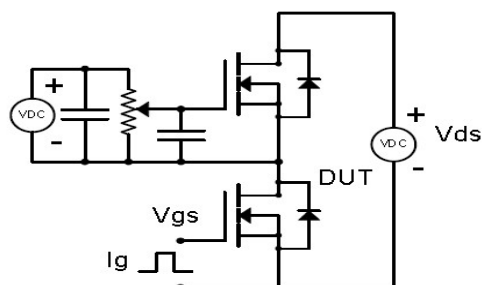


Fig 13: Max. Transient Thermal Impedance

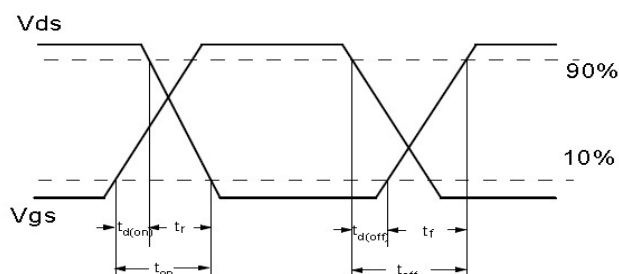
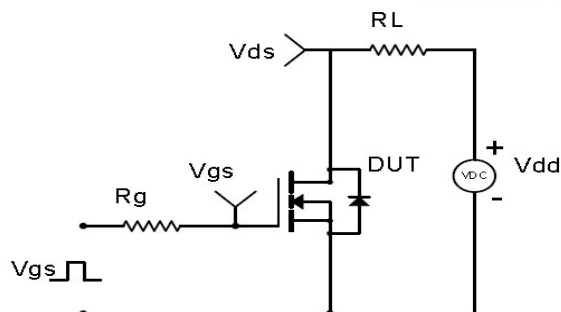


Test Circuit & Waveform

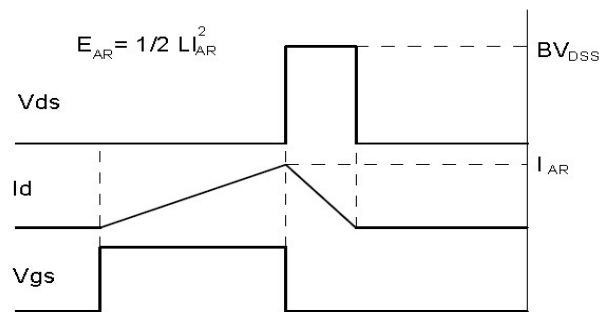
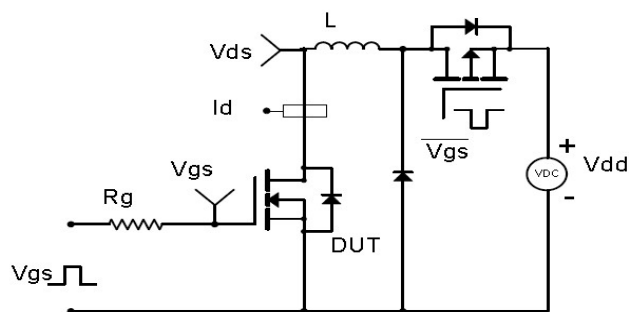
Gate Charge Test Circuit & Waveform



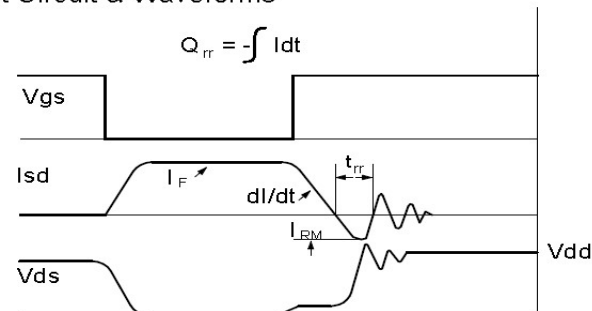
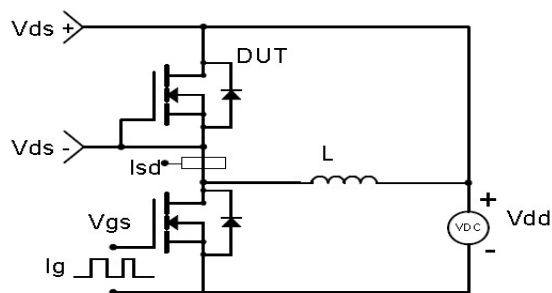
Resistive Switching Test Circuit & Waveforms



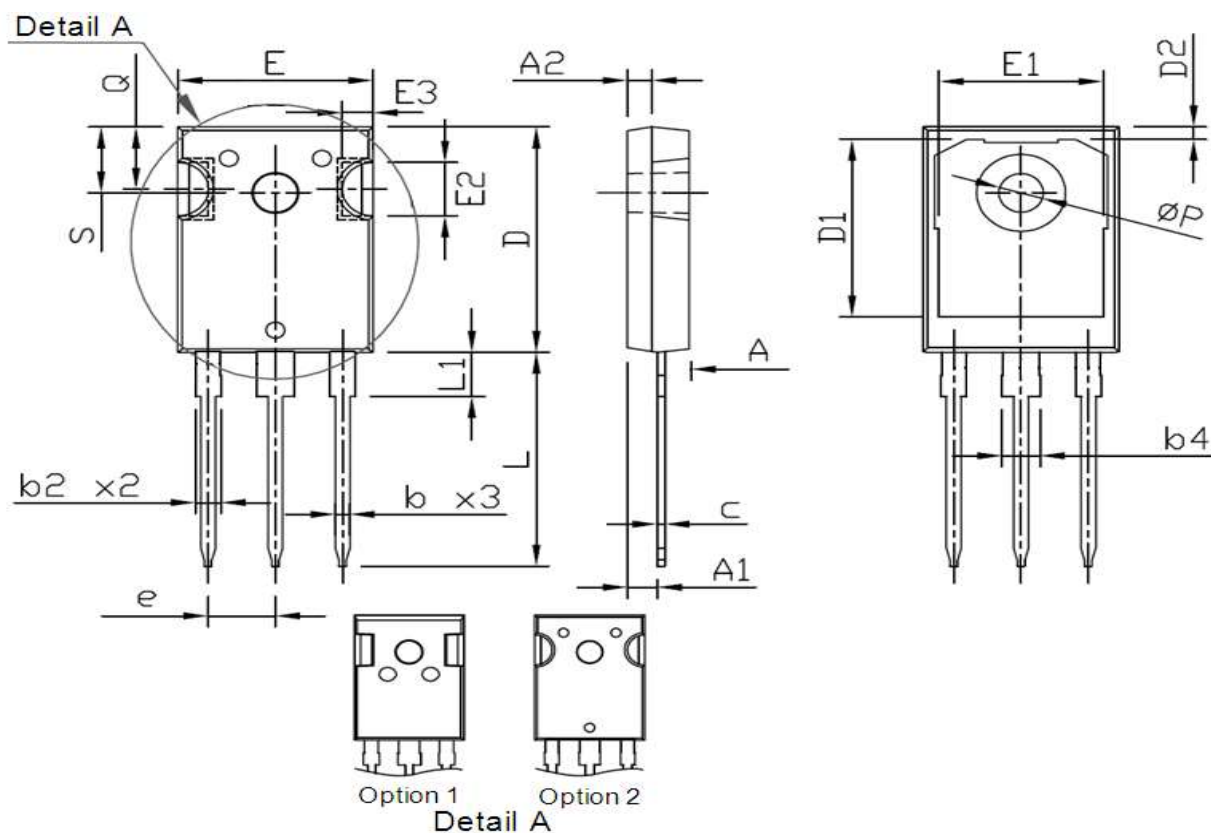
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-247-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.70	5.30	0.185	0.209
A1	2.20	2.60	0.087	0.102
A2	1.50	2.49	0.059	0.098
b	1.04	1.33	0.041	0.052
b2	1.90	2.41	0.075	0.095
b4	2.87	3.43	0.113	0.135
c	0.55	0.70	0.022	0.028
D	20.70	21.30	0.815	0.839
D1	16.25	17.65	0.640	0.695
D2	0.51	1.40	0.020	0.055
e	5.44 BSC.		0.214 BSC.	
E	15.50	16.30	0.610	0.642
E1	13.08	14.16	0.515	0.557
E2	3.80	5.49	0.150	0.216
E3	1.00	2.75	0.039	0.108
L	19.72	20.32	0.776	0.800
L1	3.85	4.50	0.152	0.177
Q	5.25	6.25	0.207	0.246
P	3.50	3.70	0.138	0.146
S	6.04	6.30	0.238	0.248

Marking**NOTE:**

NXBBAAAA

N —WB code (Usually omitted)

X —Assembly location code

BB —Fab code

AAAA —Lot code

Revision History

Revision	Date	Major changes
1.1	2023/7/9	Update top&bottom view

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.